

FDS4501H

Complementary PowerTrench® Half-Bridge MOSFET

General Description

This complementary MOSFET half-bridge device is produced using Fairchild's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain low gate charge for superior switching performance.

Applications

- DC/DC converter
- · Power management
- · Load switch
- · Battery protection

Features

Q1: N-Channel

9.3A, 30V $R_{DS(on)} = 0.018\Omega @ V_{GS} = 10V$

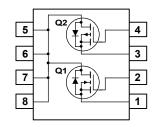
 $R_{DS(on)} = 0.027\Omega @ V_{GS} = 4.5V$

Q2: P-Channel

-2.4A, -20V $R_{DS(on)} = 0.050\Omega$ @ $V_{GS} = -4.5V$

 $R_{DS(on)} = 0.063\Omega$ @ $V_{GS} = -2.5V$





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Q1	Q2	Units
V _{DSS}	Drain-Source Voltage		30	-20	V
V _{GSS}	Gate-Source Voltage		±20	±8	V
I _D	Drain Current - Continuous	(Note 1a)	9.3	- 2.4	Α
	- Pulsed		20	- 20	
P_D	Power Dissipation for Single Operation	(Note 1a)	2.	W	
		(Note 1b)	1.		
		(Note 1c)	1		
T _J , T _{STG}	Operating and Storage Junction Temperat	ure Range	-55 to	+150	°C

Thermal Characteristics

R _{θJA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
R _{θJC}	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity	
FDS4501H	FDS4501H	13"	12mm	2500 units	

Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
Off Cha	racteristics					-	
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$ $V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	Q1 Q2	30 -20			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μA , Referenced to 25°C	Q1 Q2		24 -13		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V V _{DS} = -16 V, V _{GS} = 0 V	Q1 Q2			1 -1	μА
I _{GSS}	Gate-Body Leakage	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$ $V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$	Q1 Q2			<u>+</u> 100 <u>+</u> 100	nA
On Cha	racteristics (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$ $V_{DS} = V_{GS}, I_D = -250 \mu A$	Q1 Q2	1 -0.4	1.6 7	3 –1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μA , Referenced to 25°C	Q1 Q2		-4 3		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 9.3 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 9.3 \text{ A}, T_J = 125^{\circ}\text{C}$ $V_{GS} = 4.5 \text{ V}, I_D = 7.6 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -2.4 \text{ A}$	Q1 Q2		14 21 17 36	18 29 27 50	mΩ
		$V_{GS} = -4.5 \text{ V}, I_D = -2.4 \text{A}, T_J = 125 ^{\circ}\text{C}$	Q2		49 47	80 63	
$I_{D(on)}$	On-State Drain Current	$V_{GS} = -2.5 \text{ V}, I_D = -2.0 \text{ A}$ $V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$ $V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$	Q1 Q2	20 –20			Α
g FS	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 9.3 \text{ A}$ $V_{DS} = 5 \text{ V}, I_{D} = -2.4 \text{ A}$	Q1 Q2		28 12		S
Dynami	c Characteristics						
C _{iss}	Input Capacitance	V _{DS} = 10 V, V _{GS} = 0 V, f = 1.0 MHz	Q1 Q2		1958 1312		pF
Coss	Output Capacitance		Q1 Q2		424 240		pF
C _{rss}	Reverse Transfer Capacitance		Q1 Q2		182 106		pF

Electrical Characteristics (continued)

r (k

T_A = 25°C unless otherwise noted

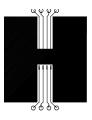
Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
Switchin	g Characteristics (Note 2)					
$t_{\text{d(on)}}$	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, I_{D} = 1 \text{ A},$ $V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	Q1 Q2		15 15	27 27	ns
t _r	Turn-On Rise Time		Q1 Q2		5 15	10 27	ns
$t_{d(off)}$	Turn-Off Delay Time		Q1 Q2		38 40	61 64	ns
t _f	Turn-Off Fall Time		Q1 Q2		10 25	20 40	ns
Q_g	Total Gate Charge	Q1 V _{DS} = 15 V, I _D = 9.3 A, V _{GS} = 4.5 V	Q1 Q2		17 13	27 21	nC
Q_{gs}	Gate-Source Charge	Q2	Q1 Q2		4 2.5		nC
Q_{gd}	Gate-Drain Charge	V_{DS} = 15 V, I_{D} = -2.4 A, V_{GS} = -4.5 V	Q1 Q2		5 2.0		nC

Drain-Source Diode Characteristics and Maximum Ratings

Is	Maximum Continuous Drain-S	Source Diode Forward Current	Q1	2.1	Α
			Q2	-2.1	
V_{SD}	Drain-Source Diode Forward	$V_{GS} = 0 \text{ V}, I_{S} = 2.1 \text{ A} \text{ (Note 2)}$	Q1	1.2	V
	Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -2.1 \text{ A} \text{ (Note 2)}$	Q2	-1.2	

Notes:

 R_{8JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{8JC} is guaranteed by design while R_{8CA} is determined by the user's board design.



a) 50°/W when mounted on a 1 in² pad of 2 oz copper



b) 105°/W when mounted on a 0.04 in² pad of 2 oz



c) 125°/W when mounted on a minimum pad.

Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%

Typical Characteristics: Q2

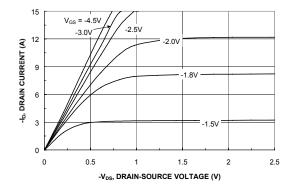


Figure 1. On-Region Characteristics.

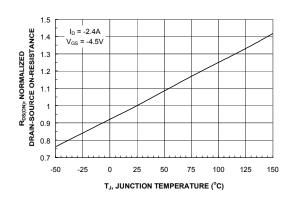


Figure 3. On-Resistance Variation with Temperature.

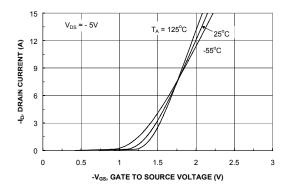


Figure 5. Transfer Characteristics.

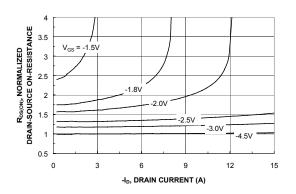


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

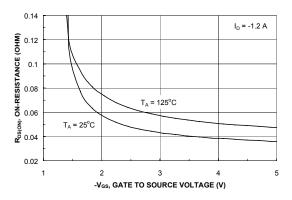


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

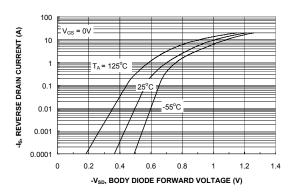
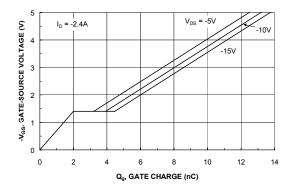


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics: Q2



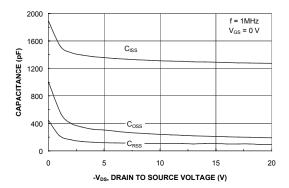
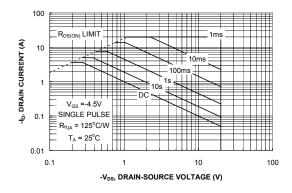


Figure 7. Gate Charge Characteristics.

Figure 8. Capacitance Characteristics.



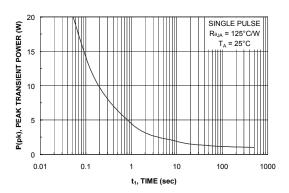


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

Typical Characteristics: Q1

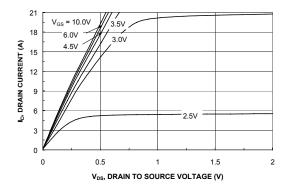


Figure 11. On-Region Characteristics.

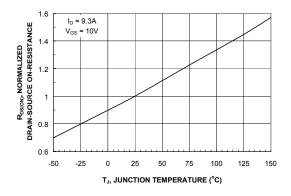


Figure 13. On-Resistance Variation with Temperature.

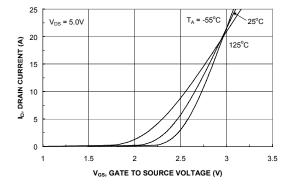


Figure 15. Transfer Characteristics.

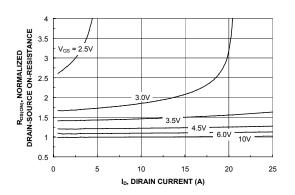


Figure 12. On-Resistance Variation with Drain Current and Gate Voltage.

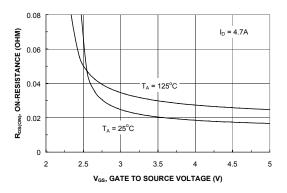


Figure 14. On-Resistance Variation with Gate-to-Source Voltage.

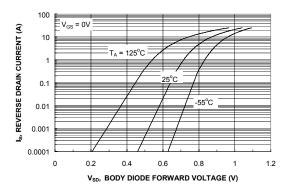
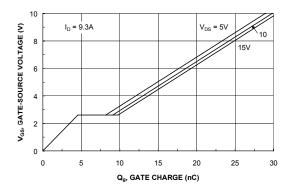


Figure 16. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics Q1



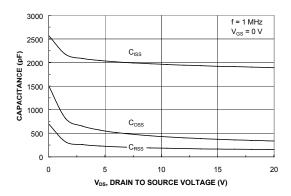


Figure 17. Gate Charge Characteristics.

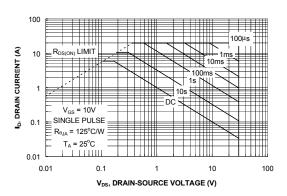


Figure 18. Capacitance Characteristics.

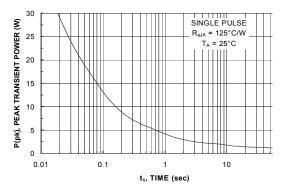


Figure 19. Maximum Safe Operating Area.



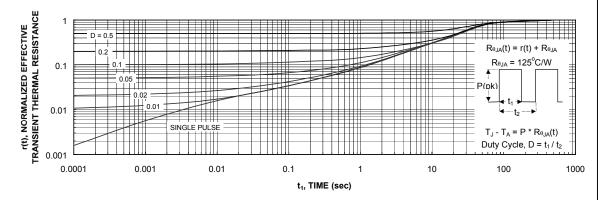
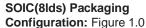


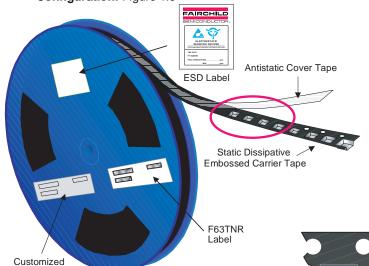
Figure 21. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

SO-8 Tape and Reel Data and Package Dimensions







Packaging Description:

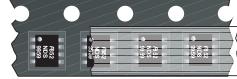
Packaging Description:

SOIC-8 parts are shipped in tape. The carrier tape is made from a dissipative (carbon filled) polycarbonate resin. The cover tape is a multilayer film (Heat Activated Adhesive in nature) primarily composed of polyester film, adhesive layer, sealant, and amit-static sprayed agent. These reeled parts in standard option are shipped with 2,500 units per 13° or 300cm diameter reel. The reels are dark blue in color and is made of polystyrene plastic (anti-static coated). Other option comes in 500 units per 7° or 177cm diameter reel. This and some other options are further described in the Packaging Information table.

These full reles are individually barcode labeled and placed inside a standard intermediate box (illustrated in figure 1.0) made of recyclable corrugated brown paper. One box contains two reels maximum. And these boxes are placed inside a barcode labeled shipping box which comes in different sizes depending on the number of parts shipped.

ESD Label

F63TN Label

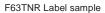




SOIC-8 Unit Orientation

343mm x 342mm x 64mm Standard Intermediate box

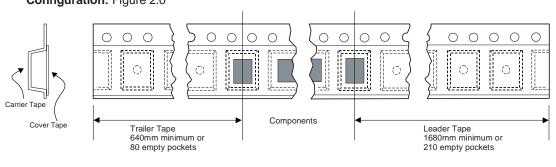
SOIC (8lds) Packaging Information Packaging Option Standard o flow code) L86Z D84Z Rail/Tube TNR Packaging type TNR TNR Qty per Reel/Tube/Bag 2.500 4.000 500 Reel Size 13" Dia 13" Dia 7" Dia Box Dimension (mm) 343y64y343 530x130x83 343y64y343 184v187v47 Max qty per Box 5,000 30,000 8,000 1,000 Weight per unit (gm) 0.0774 0.0774 0.0774 0.0774 Weight per Reel (kg) 0.6060 0.9696 0.1182 Note/Comments



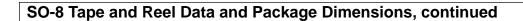
Label



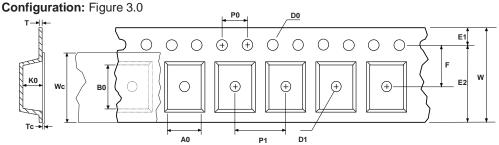
SOIC(8Ids) Tape Leader and Trailer Configuration: Figure 2.0



F63TNL



SOIC(8lds) Embossed Carrier Tape





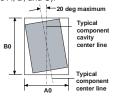
	Dimensions are in millimeter													
Pkg type	A0	В0	w	D0	D1	E1	E2	F	P1	P0	K0	т	Wc	Тс
SOIC(8lds) (12mm)	6.50 +/-0.10	5.30 +/-0.10	12.0 +/-0.3	1.55 +/-0.05	1.60 +/-0.10	1.75 +/-0.10	10.25 min	5.50 +/-0.05	8.0 +/-0.1	4.0 +/-0.1	2.1 +/-0.10	0.450 +/- 0.150	9.2 +/-0.3	0.06 +/-0.02

Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).



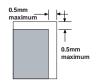
Sketch A (Side or Front Sectional View)
Component Rotation

13" Diameter Option



Sketch B (Top View)

Component Rotation



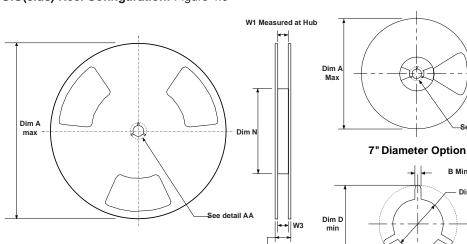
Sketch C (Top View)

Component lateral movement

Dim C

DETAIL AA

SOIC(8lds) Reel Configuration: Figure 4.0

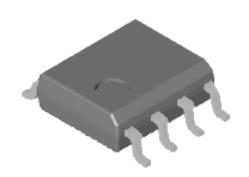


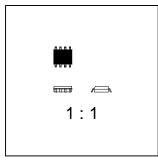
Dimensions are in inches and millimeters									
Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)
12mm	7" Dia	7.00 177.8	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	2.165 55	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4
12mm	13" Dia	13.00 330	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	7.00 178	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4

W2 max Measured at Hub

SO-8 Tape and Reel Data and Package Dimensions, continued

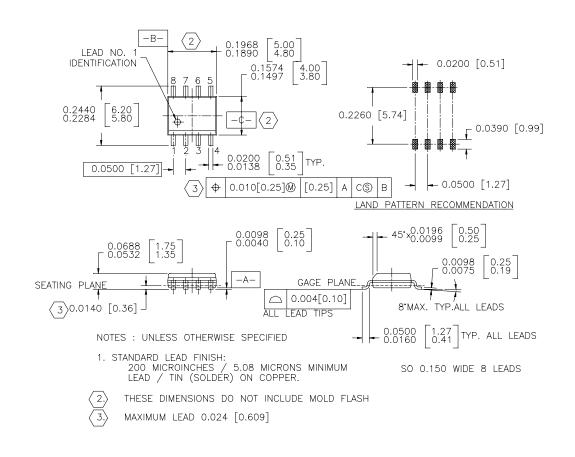
SOIC-8 (FS PKG Code S1)





Scale 1:1 on letter size paper
Dimensions shown below are in:
inches [millimeters]

Part Weight per unit (gram): 0.0774



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FAST[®] Quiet Series[™] SuperSOT[™]-3 GTO[™] SuperSOT[™]-6

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

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Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
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